

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/773,455	SHYUR ET AL.
Examiner		Art Unit
	YONG D. PAK	1652

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
435	201	12/19/2008	YP
435	440	12/19/2008	YP
536	23.2	12/19/2008	YP
STIC: SEQ ID NO:1		12/19/2008	YP